Search Notes		

;	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/757,192	DEWITT ET AL.
	Examiner	Art Unit
	Raymond Phan	2111

SEARCHED			
Class	Subclass	Date	Examiner
710	260-269	11/23/2005	RP
712	200,244	11/26/2005	RP
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SE (INCLUDIN)	ARCH NOTI)
		DATE	EXMR
EAST		11/23/2005	RP
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